

<b>Notice of References Cited</b>	Application/Control No. 10/581,302		Applicant(s)/Patent Under Reexamination HIROSE ET AL.	
	Examiner Liam J. Heincer		Art Unit 1709	Page 1 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,160,552 A	12-1964	RUSSELL CHARLES R; et. al.	162/146
*	B	US-3,390,127 A	06-1968	SCHICK JOHN W; et. al.	528/127
*	C	US-5,061,743 A	10-1991	Herring et al.	524/130
*	D	US-5,286,842 A	02-1994	Kimura, Yoshiharu	528/354
*	E	US-5,292,860 A	03-1994	Shiotani et al.	528/361
*	F	US-5,502,158 A	03-1996	Sinclair et al.	528/354
*	G	US-5,516,825 A	05-1996	Montador et al.	524/311
*	H	US-5,516,565 A	05-1996	Matsumoto, Atsushi	428/35.7
*	I	US-5,525,658 A	06-1996	Liddell et al.	524/418
*	J	US-5,536,564 A	07-1996	Noda, Isao	428/193
*	K	US-5,773,495 A	06-1998	Haschke et al.	524/52
*	L	US-5,939,467 A	08-1999	Wnuk et al.	523/128
*	M	US-6,191,203 B1	02-2001	Asrar et al.	524/317

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 09105020 A	04-1997	Japan	SHINKAWA et al.	D01F 06/62
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	McGraw, Linda, New Uses For Kenaf, August 2000, Agricultural Research
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/581,302	Applicant(s)/Patent Under Reexamination HIROSE ET AL.	
	Examiner Liam J. Heincer	Art Unit 1709	Page 2 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,214,920 B1	04-2001	Muller et al.	524/494
*	B	US-6,274,652 B1	08-2001	Uryu et al.	524/27
*	C	US-6,294,265 B1	09-2001	Ioelovich et al.	428/507
*	D	US-2002/0012759 A1	01-2002	Asayama et al.	428/34.2
*	E	US-2002/0060445 A1	05-2002	Shirk et al.	280/728.1
*	F	US-2002/0173583 A1	11-2002	Shimizu, Ken	524/515
*	G	US-6,521,717 B1	02-2003	Itoh, Hiroshi	525/444
*	H	US-2003/0078324 A1	04-2003	Terada et al.	524/115
*	I	US-6,573,340 B1	08-2003	Khemani et al.	525/437
*	J	US-6,586,503 B1	07-2003	Grohman, Martin	524/15
*	K	US-6,605,657 B1	08-2003	Favis et al.	524/52
*	L	US-2003/0181555 A1	09-2003	Figuly, Garret D.	524/284
*	M	US-6,620,869 B2	09-2003	Asrar et al.	524/133

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/581,302	Applicant(s)/Patent Under Reexamination HIROSE ET AL.	
	Examiner Liam J. Heincer	Art Unit 1709	Page 3 of 4

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0204027 A1	10-2003	Autran, Jean-Philippe Marie	525/418
*	B	US-6,632,863 B2	10-2003	Hutchison et al.	524/13
*	C	US-2004/0034121 A1	02-2004	Nozaki et al.	523/124
*	D	US-6,706,942 B1	03-2004	Zhao et al.	604/364
*	E	US-6,720,374 B2	04-2004	Sashida et al.	524/310
*	F	US-2004/0132860 A1	07-2004	Takahashi et al.	523/124
*	G	US-6,867,248 B1	03-2005	Martin et al.	523/124
*	H	US-6,878,758 B2	04-2005	Martin et al.	523/124
*	I	US-2005/0148698 A1	07-2005	Ratzsch et al.	524/035
*	J	US-2005/0215672 A1	09-2005	Mohanty et al.	524/009
*	K	US-2005/0209377 A1	09-2005	Padwa, Allen R.	524/099
*	L	US-2006/0057692 A1	03-2006	Narasimhan et al.	435/135
*	M	US-7,077,994 B2	07-2006	Bond et al.	422/1

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/581,302	Applicant(s)/Patent Under Reexamination HIROSE ET AL.	
	Examiner Liam J. Heincer	Art Unit 1709	Page 4 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0147695 A1	07-2006	Serizawa et al.	428/297.4
*	B	US-7,094,840 B2	08-2006	Whitehouse et al.	525/450
*	C	US-2006/0258833 A1	11-2006	Senda et al.	528/272
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.